US00D420927S

United States Patent [19]

Yano

[11] **Patent Number: Des. 420,927**

[45] **Date of Patent: ** Feb. 22, 2000**

[54] **IC TEST-HEAD STAND**

[75] Inventor: **Takayuki Yano**, Tokyo, Japan

[73] Assignee: **Advantest Corporation**, Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **29/098,530**

[22] Filed: **Dec. 30, 1998**

[51] **LOC (7) Cl.** **10-04**

[52] **U.S. Cl.** **D10/80**; D34/12

[58] **Field of Search** D10/80, 108; D34/12, D34/17; 37/265, 434, 285; 280/47.24; 294/54.5, 55

[56] **References Cited**

U.S. PATENT DOCUMENTS

D. 286,698	11/1986	Spicer	D34/12 X
D. 383,582	9/1997	Sinclair, Jr.	D34/12 X

Primary Examiner—Antoine Duval Davis
Attorney, Agent, or Firm—Birch, Stewart, Kolasch & Birch, LLP

[57] **CLAIM**

The ornamental design for an IC test-head stand, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of an IC test-head stand according to a first embodiment of the present design.

FIG. **2** is a front view of the IC test-head stand shown in FIG. **1**. A rear view of the IC test-head stand is omitted from the drawing since the rear view is symmetrical with the front view.

FIG. **3** is a left side view of the IC test-head stand shown in FIG. **1**.

FIG. **4** is a right side view of the IC test-head stand shown in FIG. **1**.

FIG. **5** is a top plan view of the IC test-head stand shown in FIG. **1**.

FIG. **6** is a bottom plan view of the IC test-head stand shown in FIG. **1**.

FIG. **7** is a perspective view of an IC test-head stand according to a second embodiment of the present design.

FIG. **8** is a front view of the IC test-head stand shown in FIG. **7**. A rear view of the IC test-head stand is omitted from the drawing since the rear view is symmetrical with the front view.

FIG. **9** is a left side view of the IC test-head stand shown in FIG. **7**.

FIG. **10** is a right side view of the IC test-head stand shown in FIG. **7**.

FIG. **11** is a top plan view of the IC test-head stand shown in FIG. **7**.

FIG. **12** is a bottom plan view of the IC test-head stand shown in FIG. **7**.

FIG. **13** is a perspective view of an IC test-head stand according to a third embodiment of the present design.

FIG. **14** is a front view of the IC test-head stand shown in FIG. **13**. A rear view of the IC test-head stand is omitted from the drawing since the rear view is symmetrical with the front view.

FIG. **15** is a left side view of the IC test-head stand shown in FIG. **13**.

FIG. **16** is a right side view of the IC test-head stand shown in FIG. **13**.

FIG. **17** is a top plan view of the IC test-head stand shown in FIG. **13**.

FIG. **18** is a bottom plan view of the IC test-head stand shown in FIG. **13**; and,

FIG. **19** is a front view of the IC test-head stand shown in FIG. **1**, for illustrating the use of the IC test-head stand.

The broken line showing is for illustrative purposes only and forms no part of the claimed design.

1 Claim, 10 Drawing Sheets

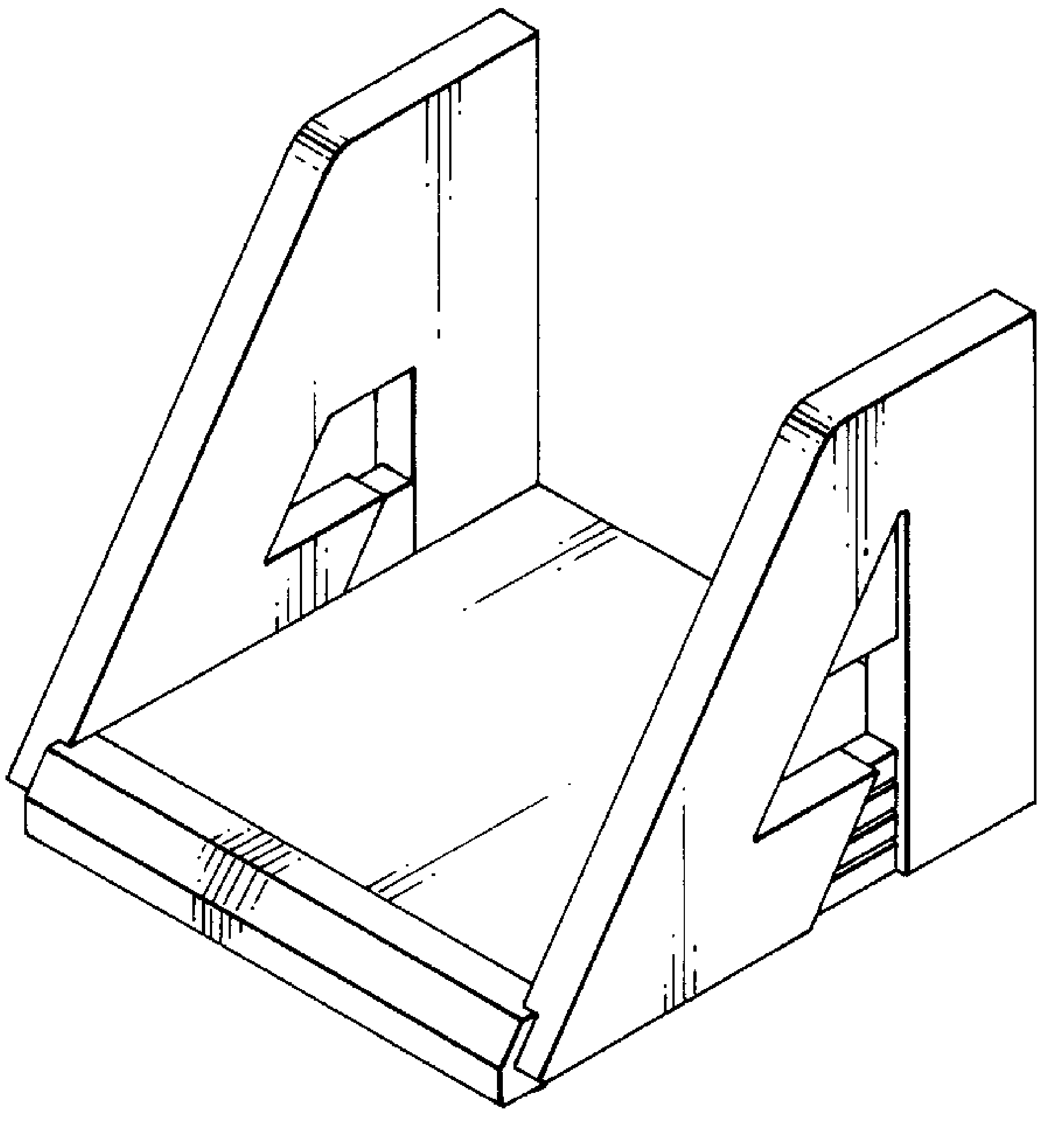


FIG. 1

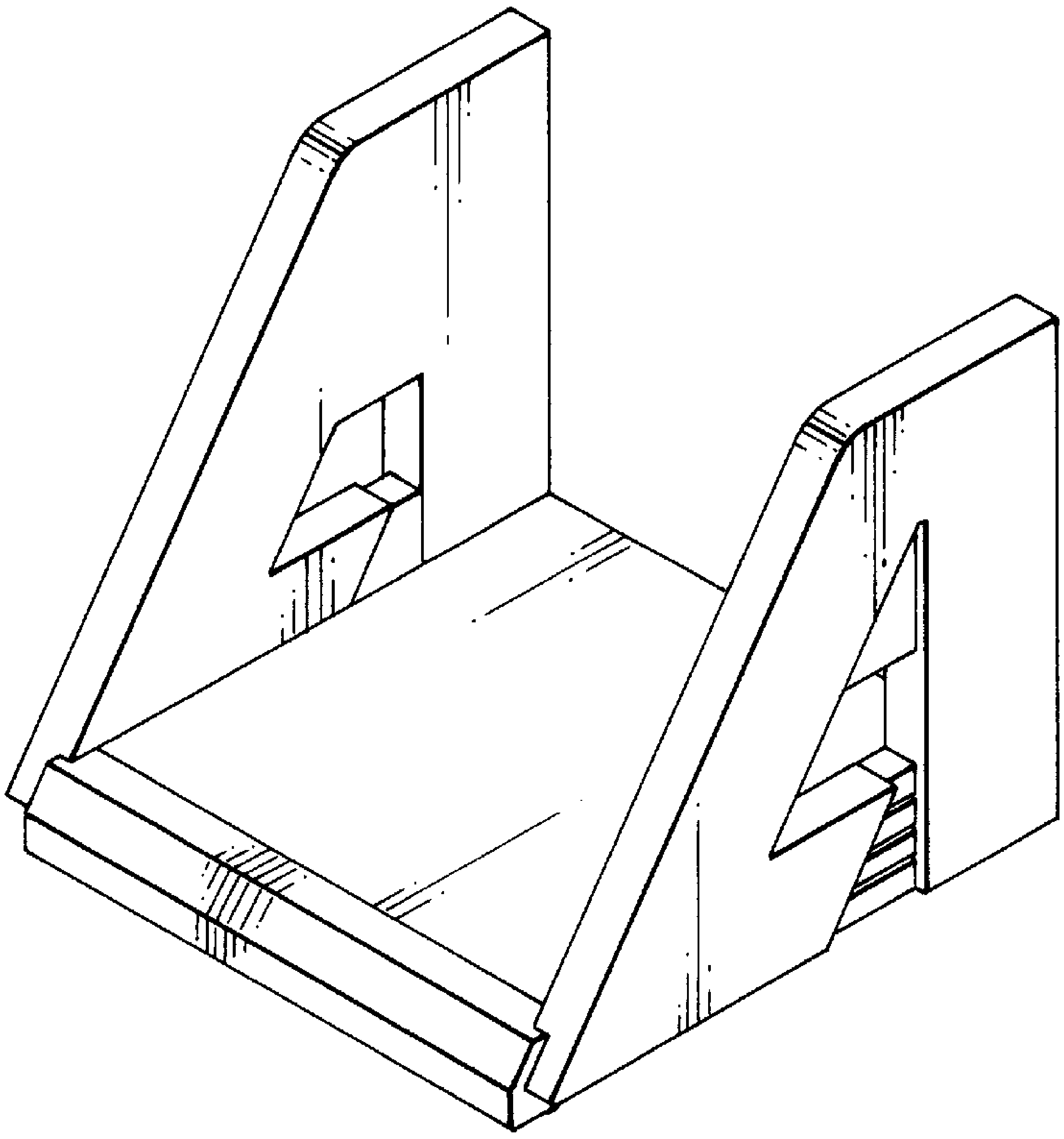


FIG. 2

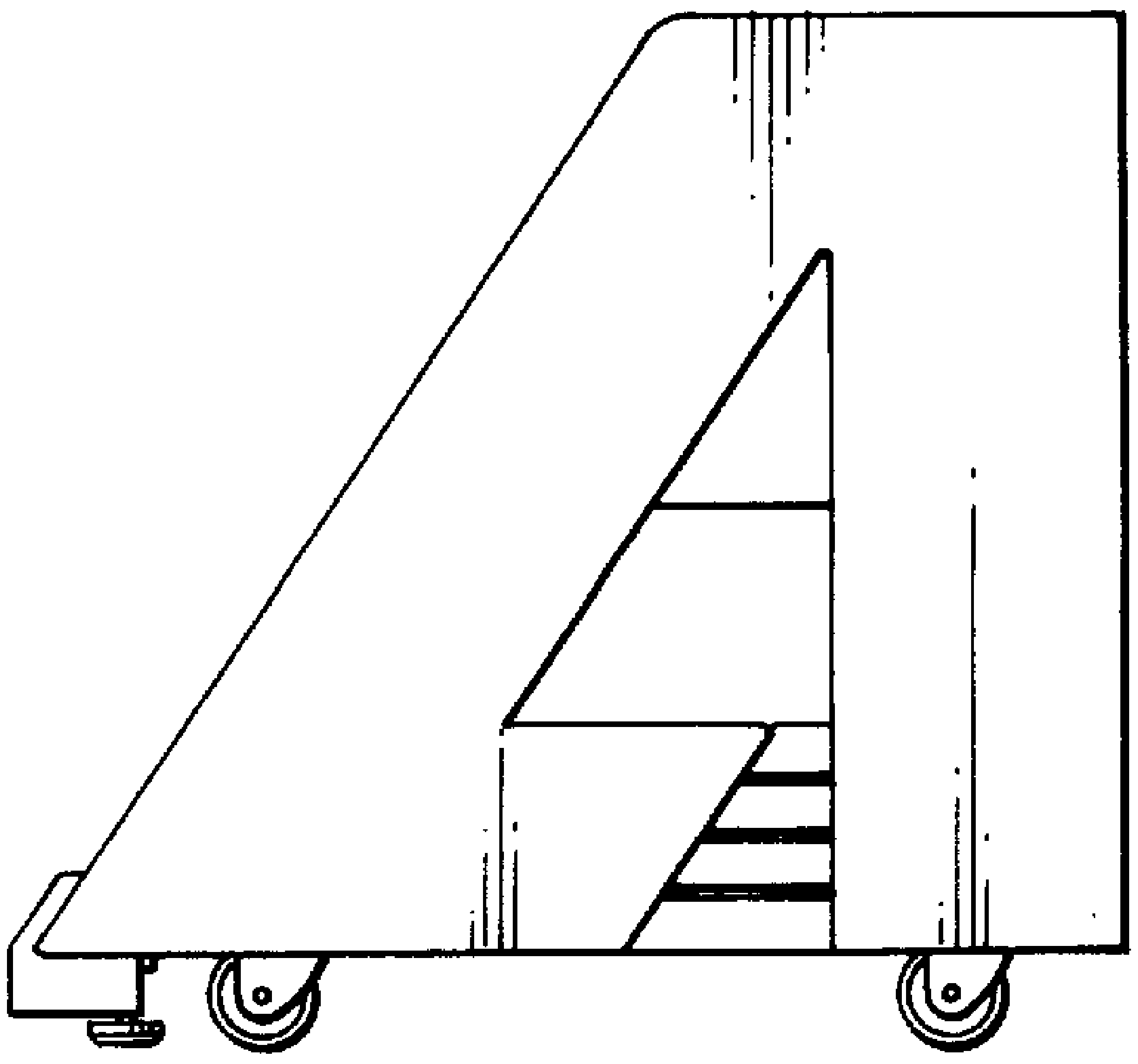
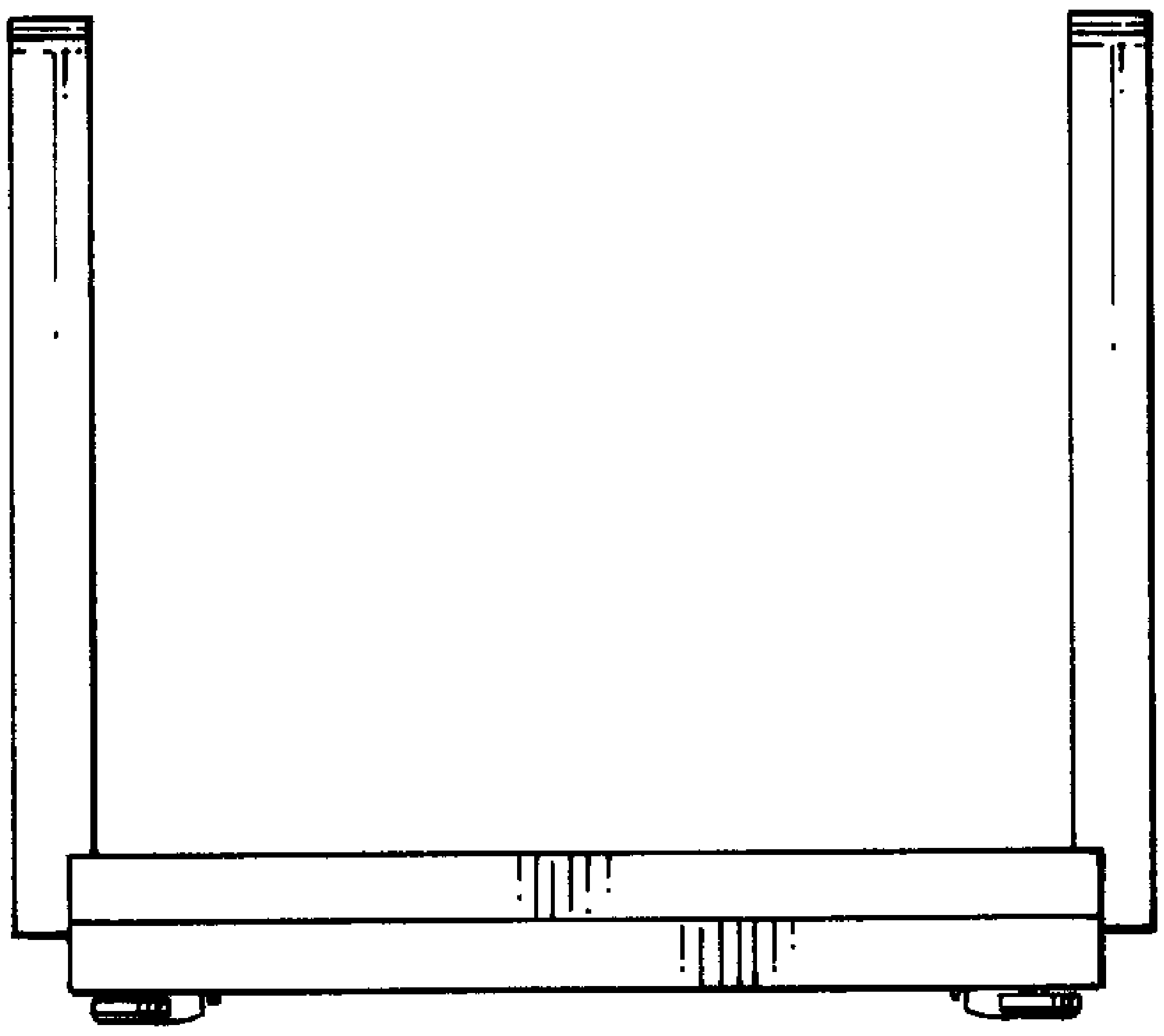


FIG. 3



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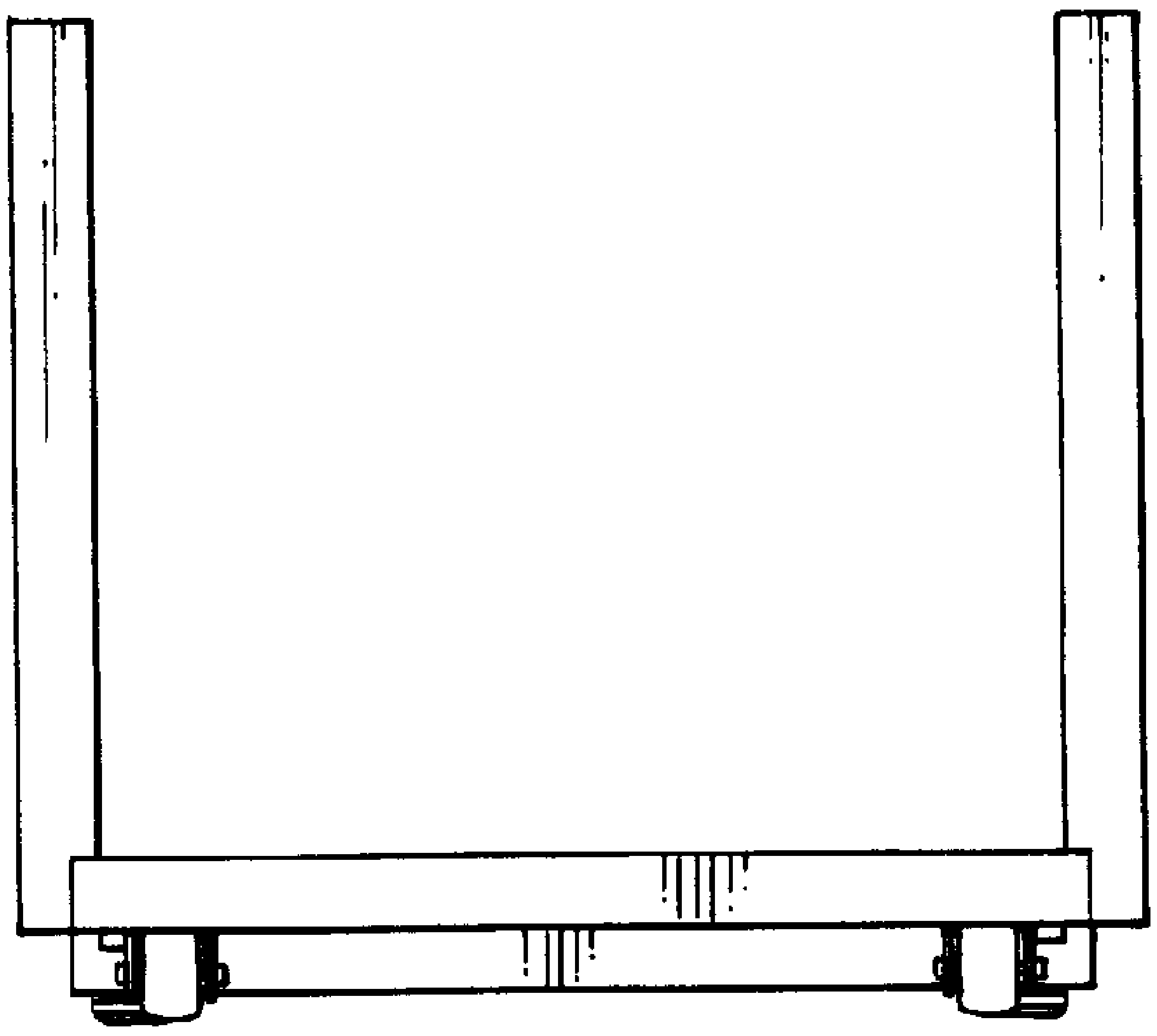

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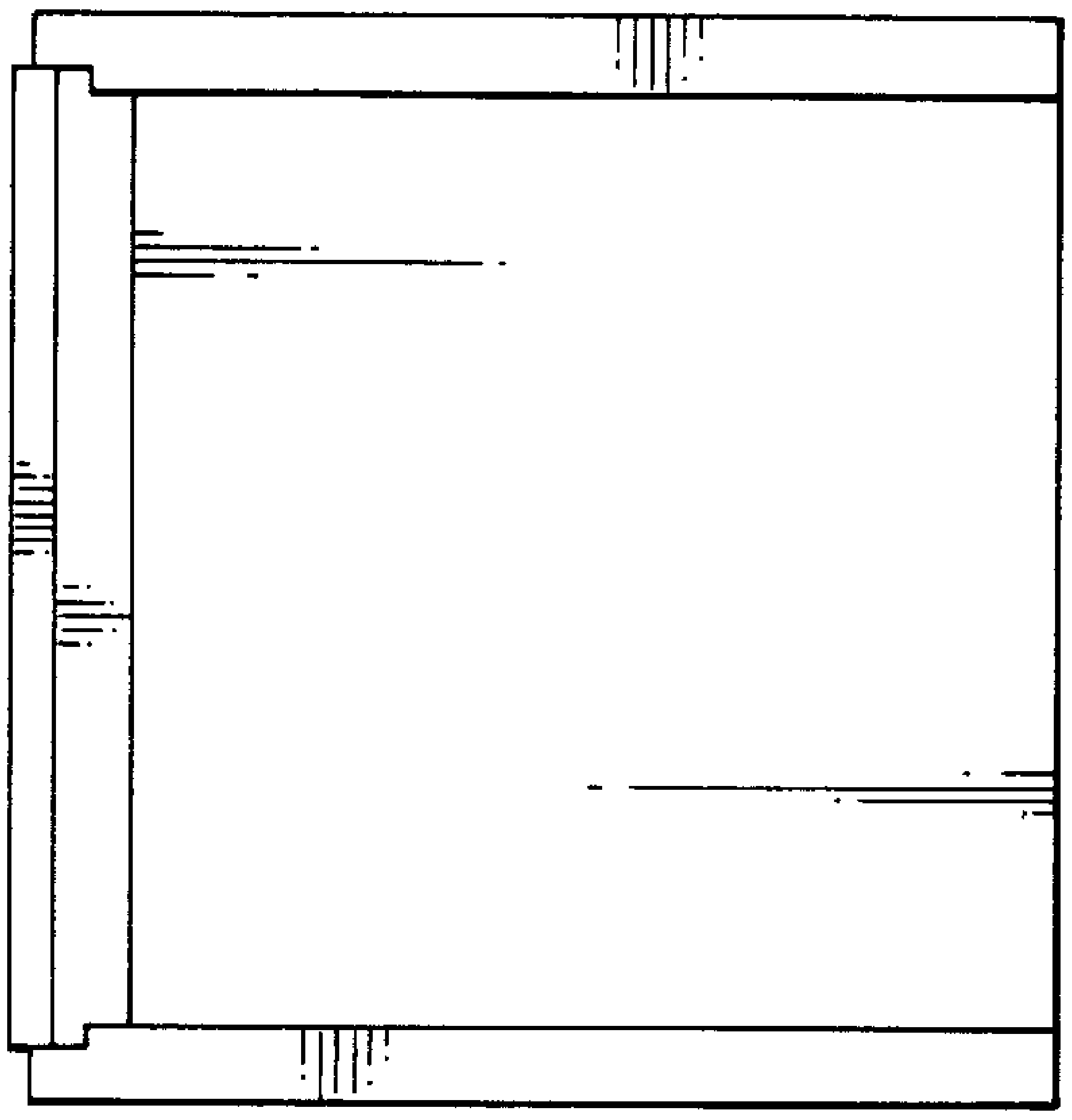

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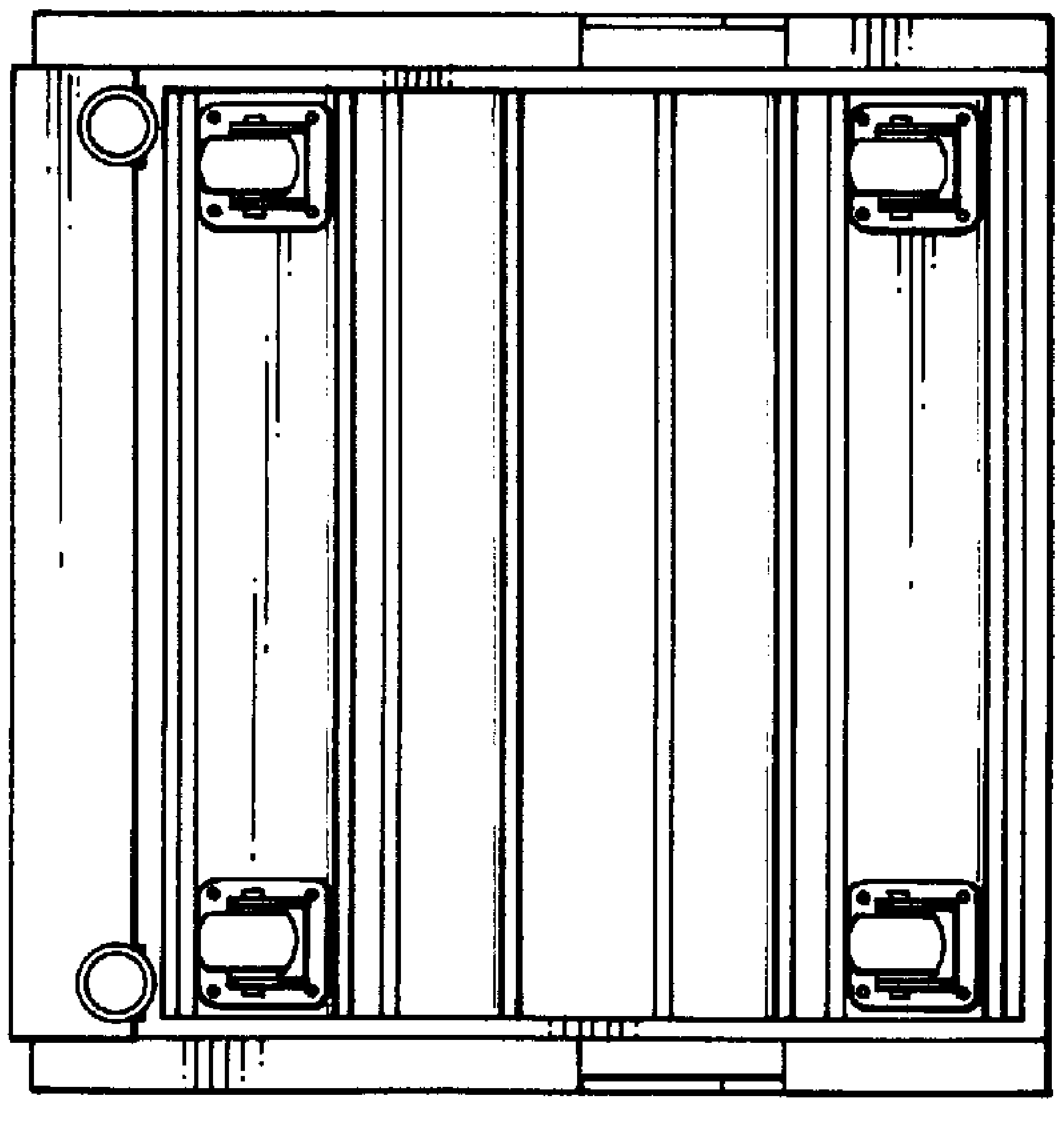

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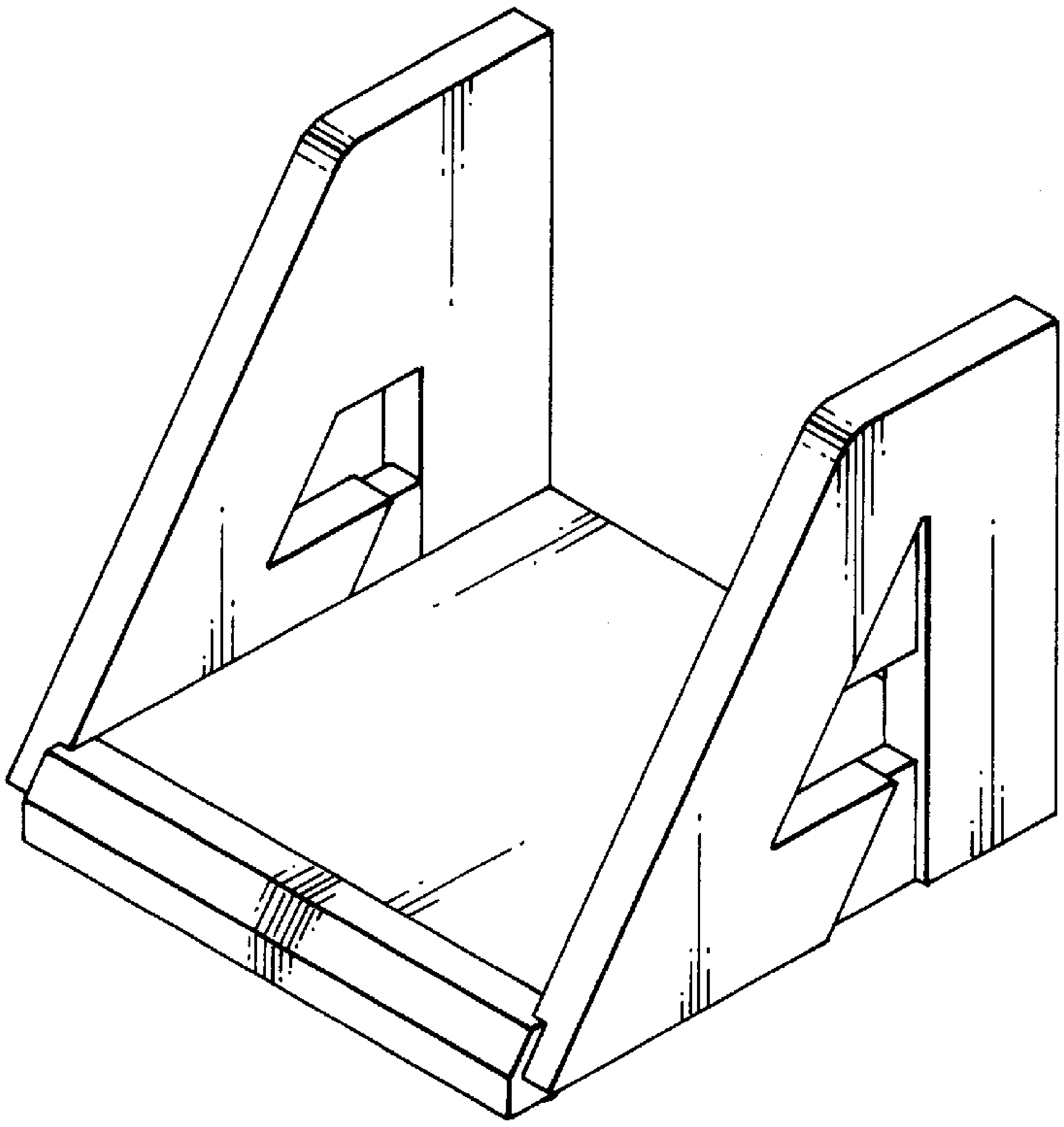

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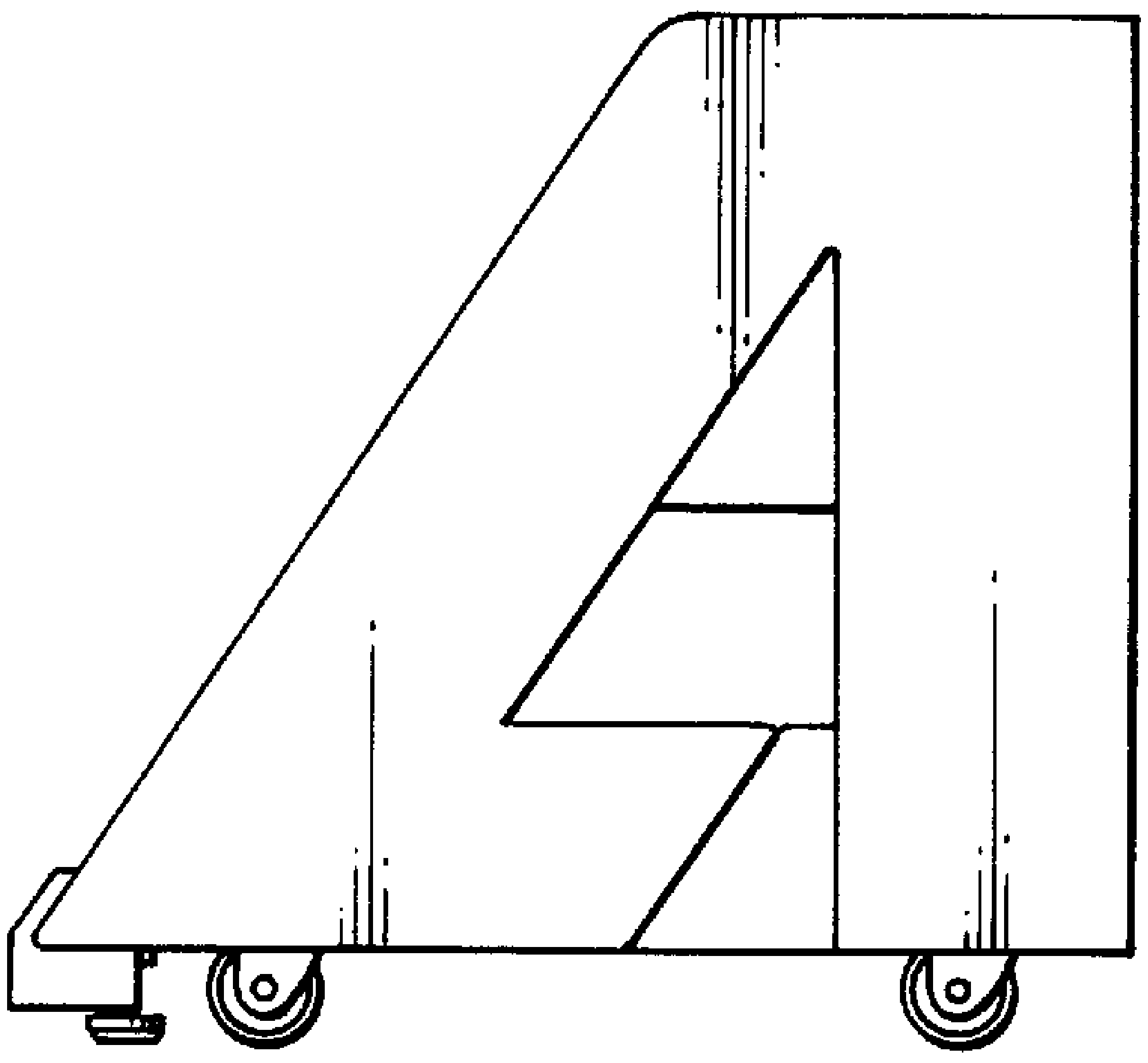
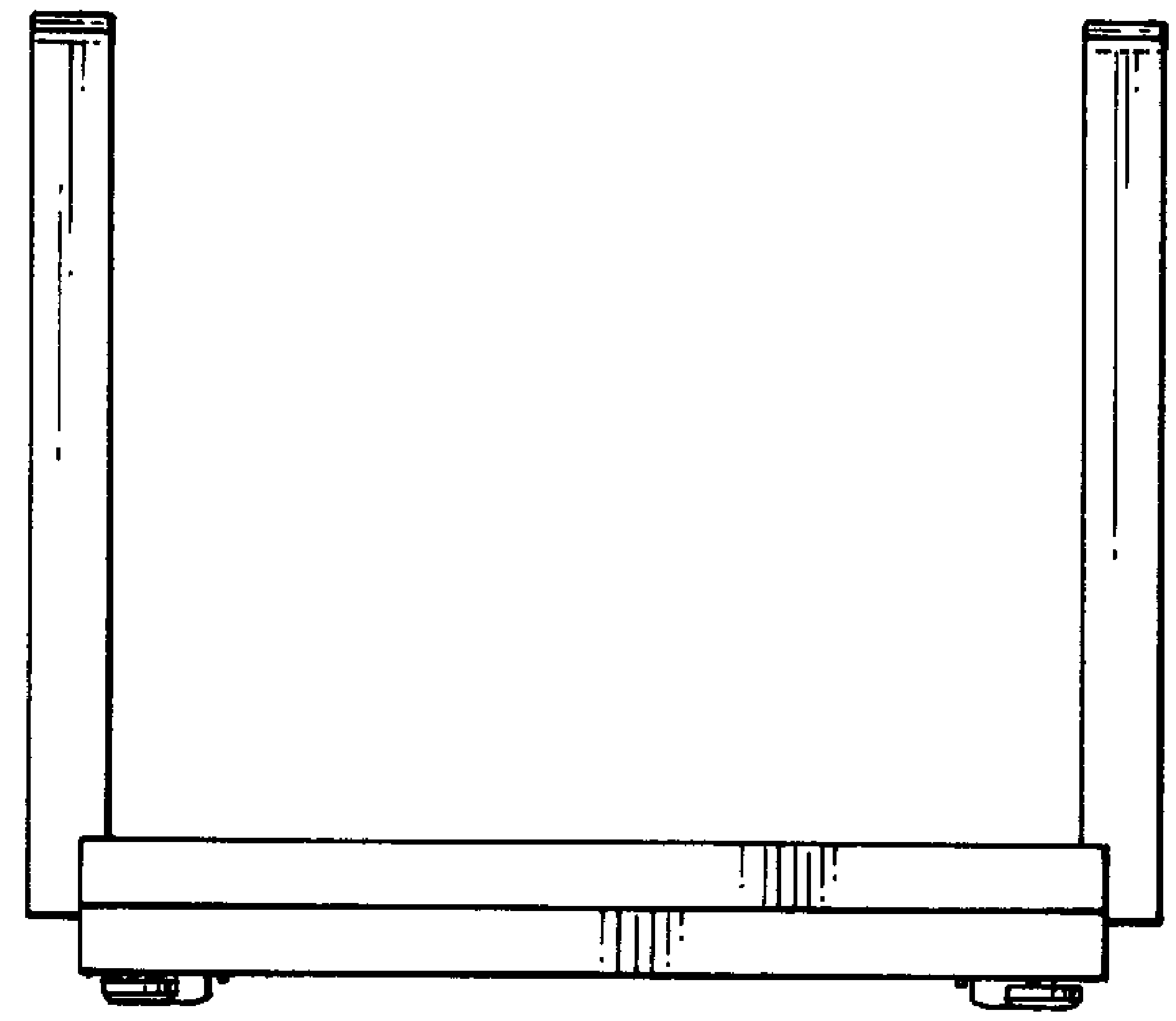


FIG. 9



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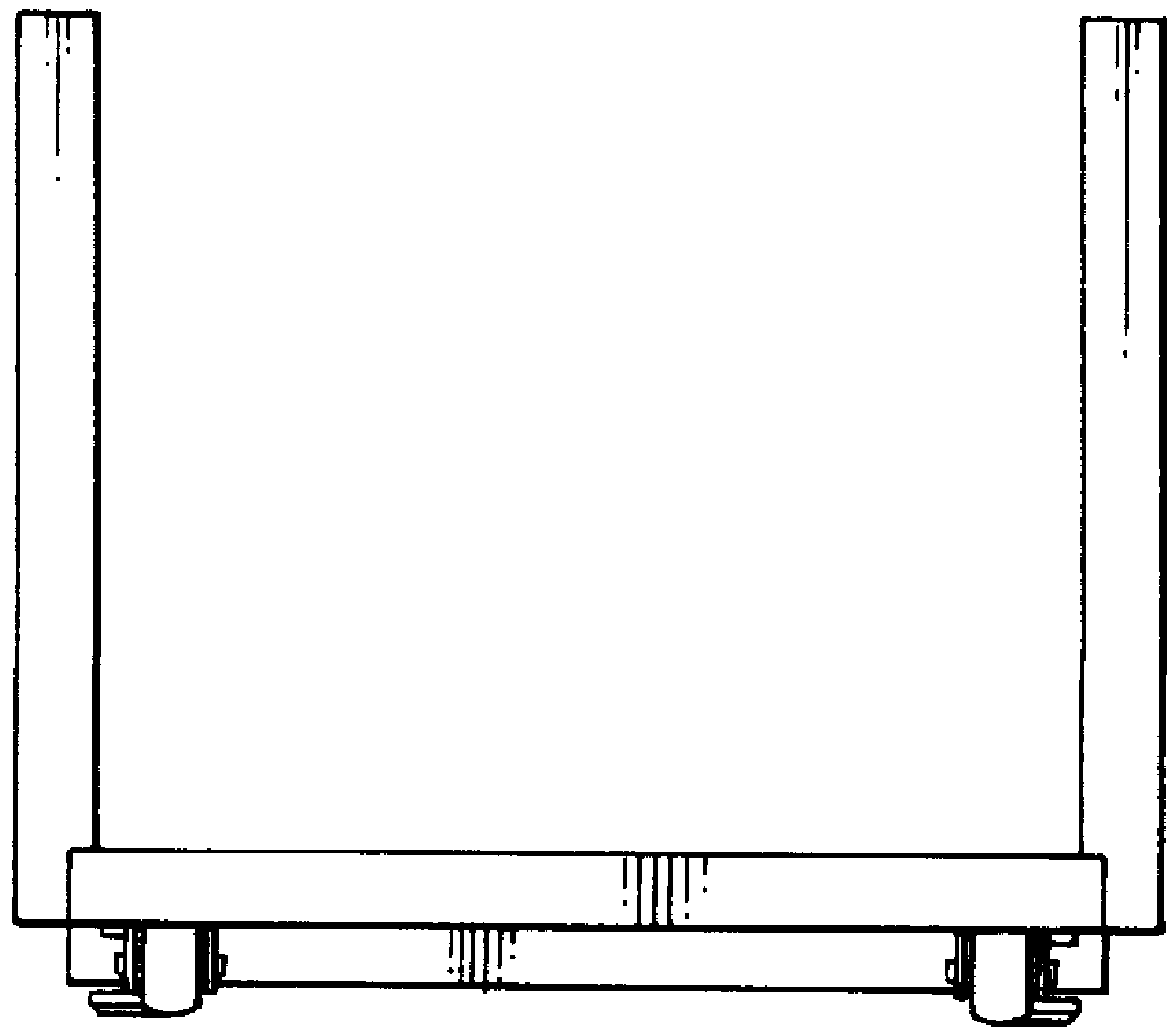
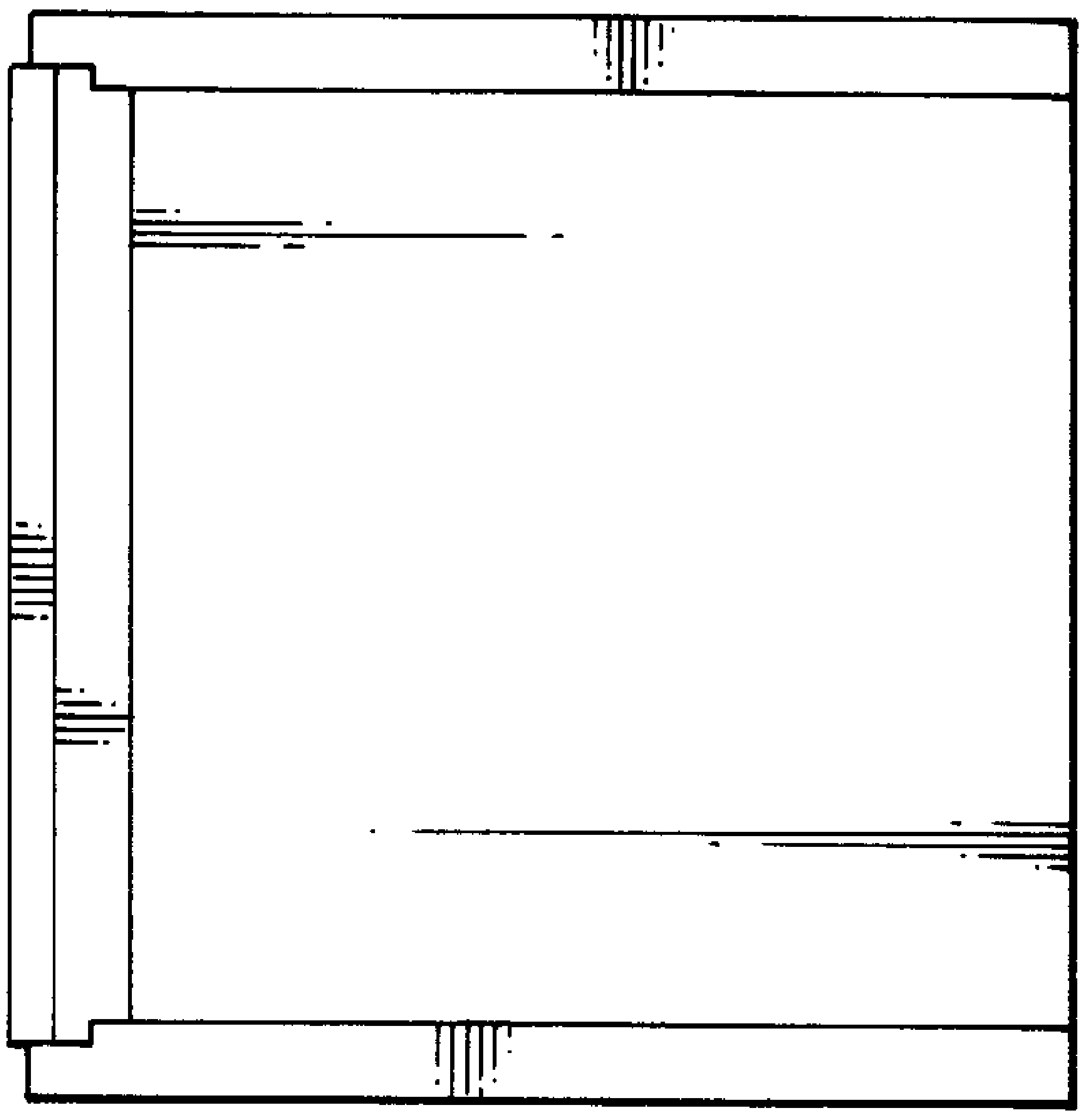


FIG. 11



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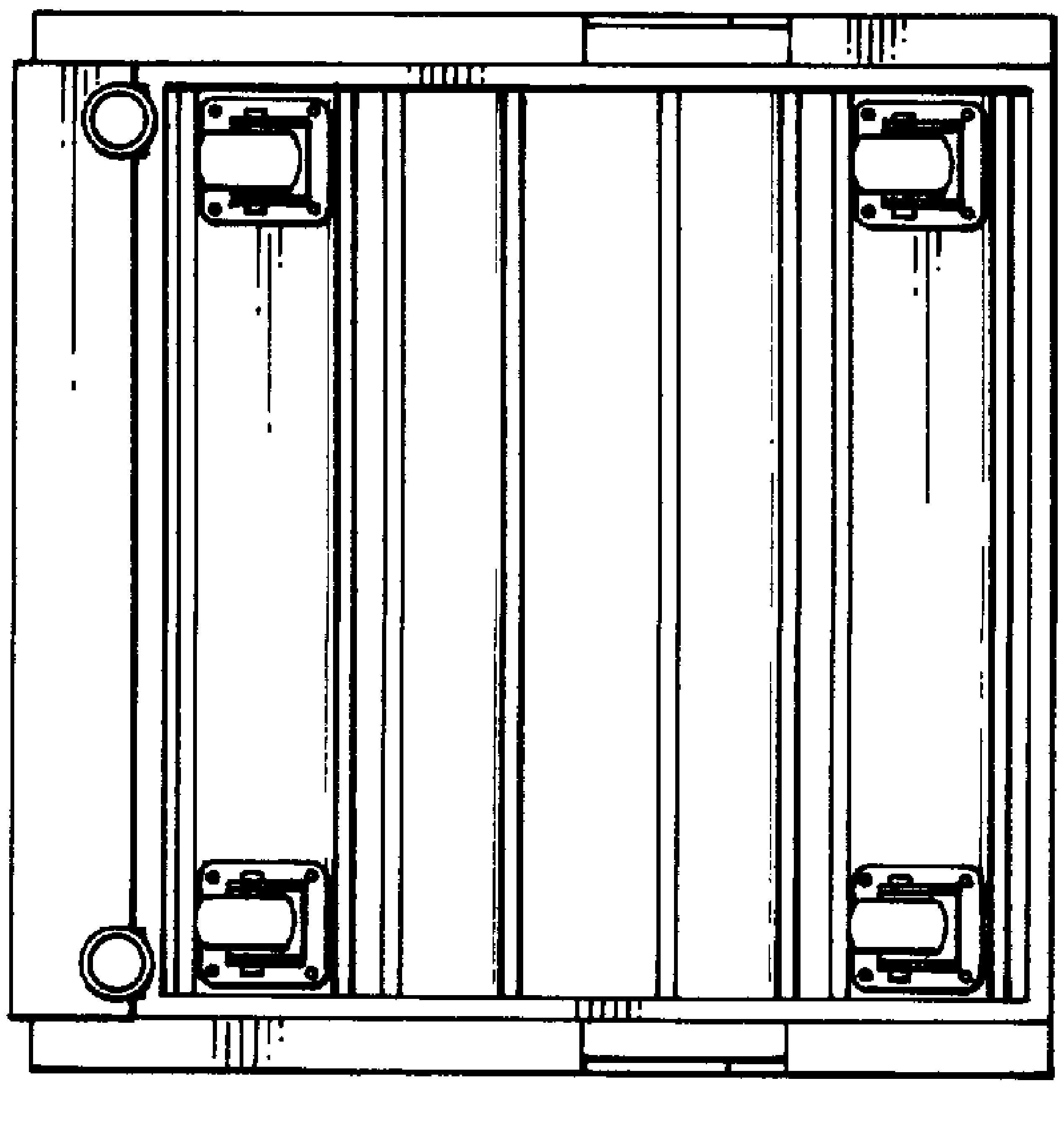

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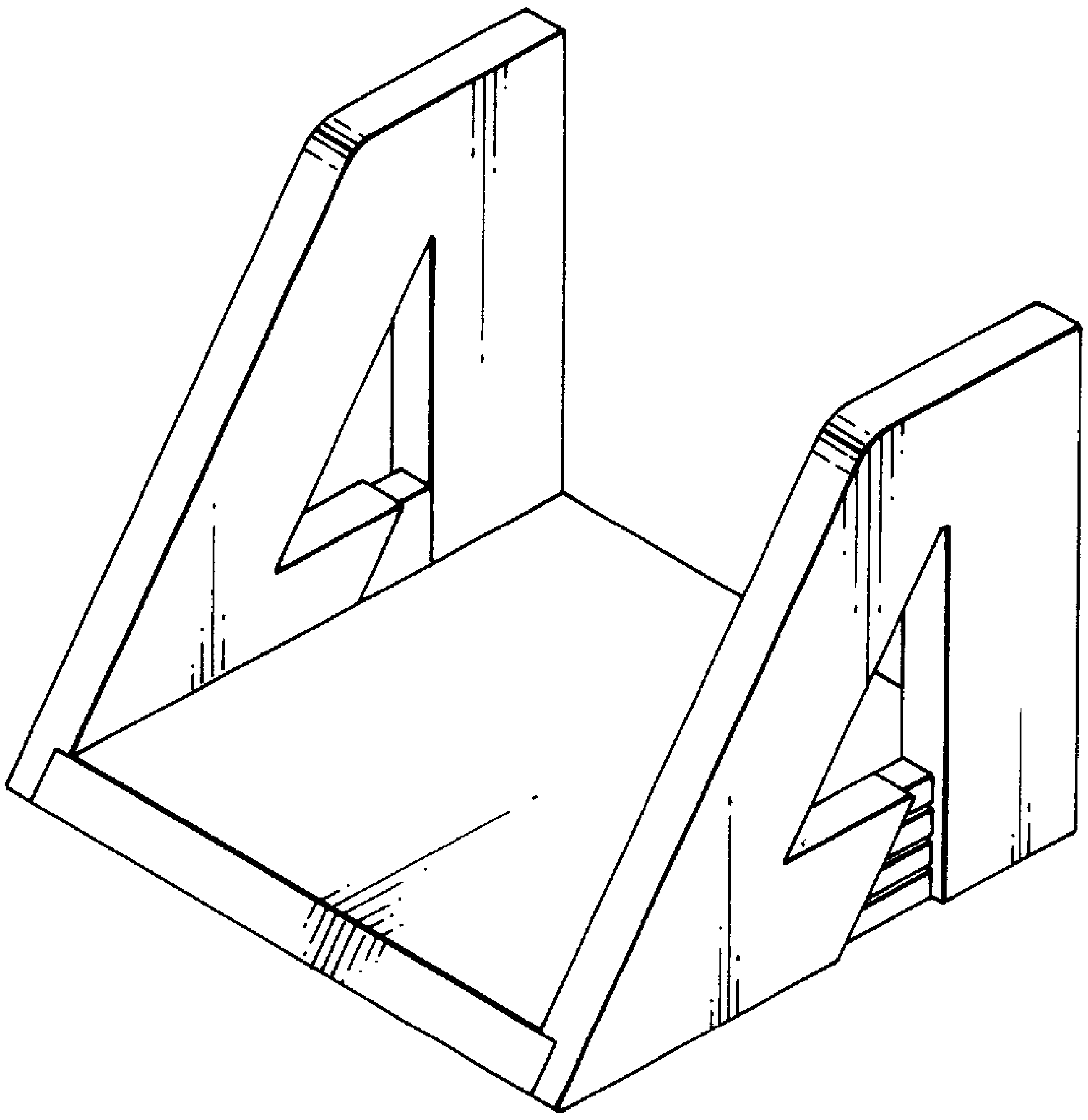


FIG. 14

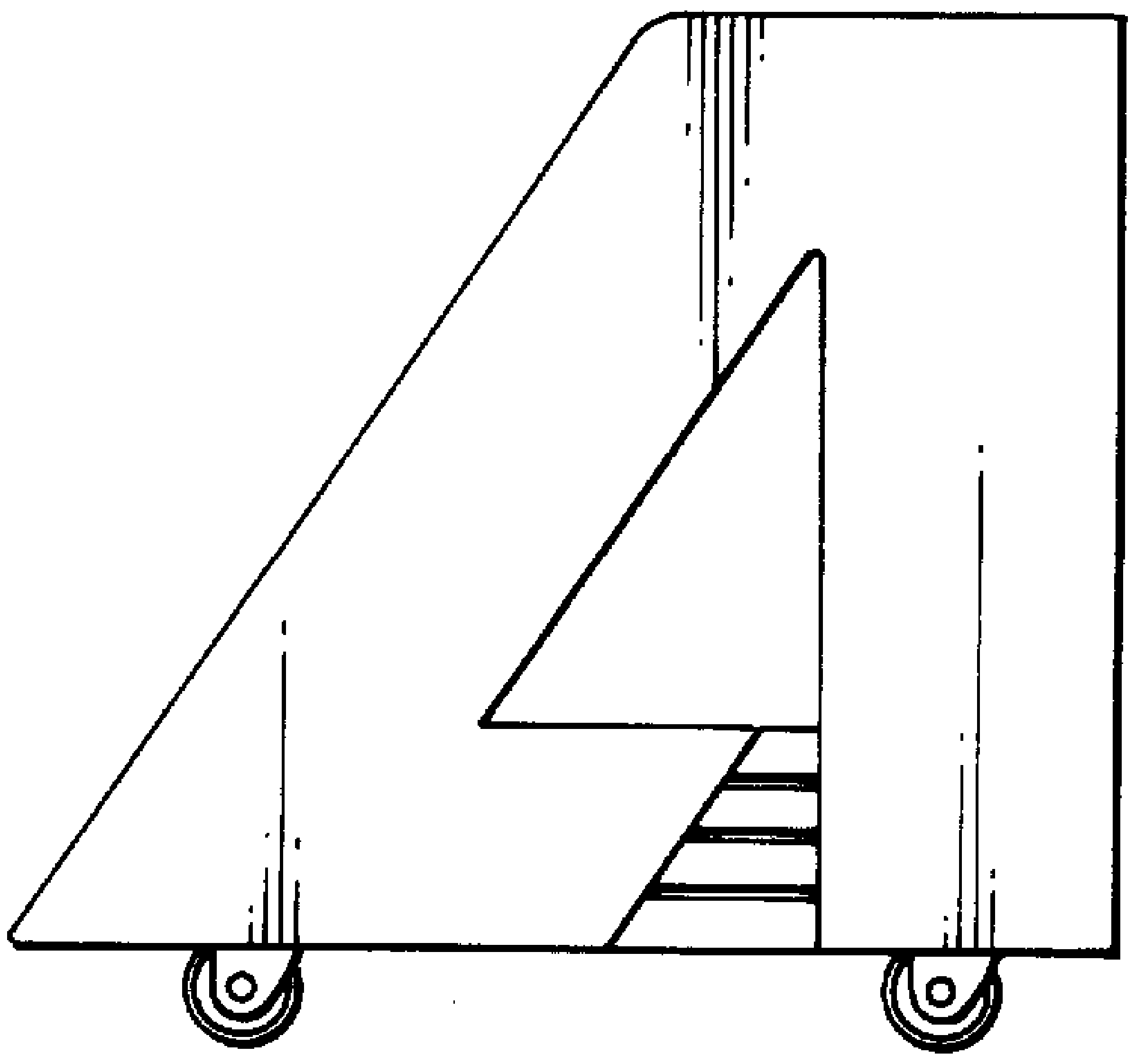


FIG. 15

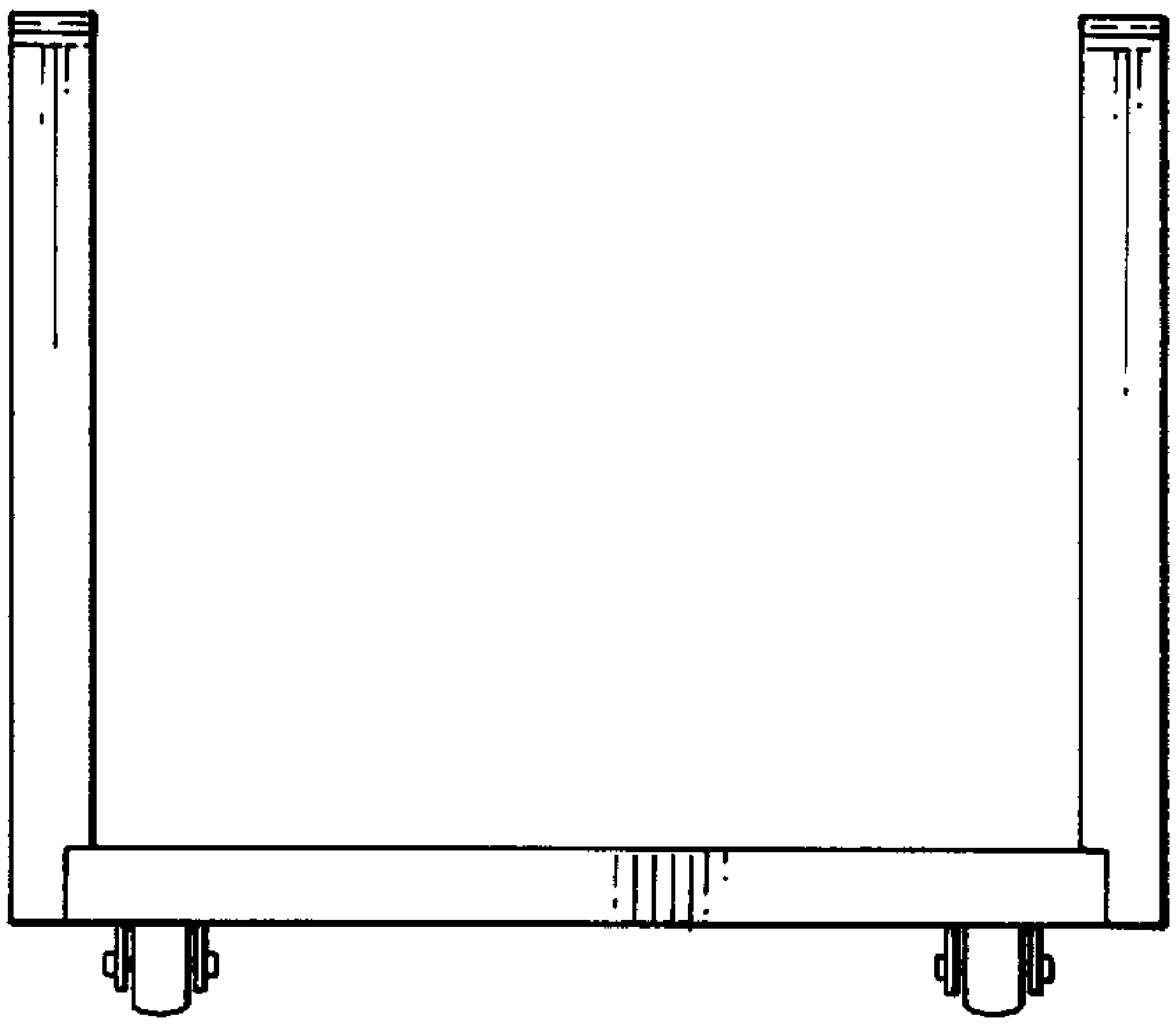


FIG. 16

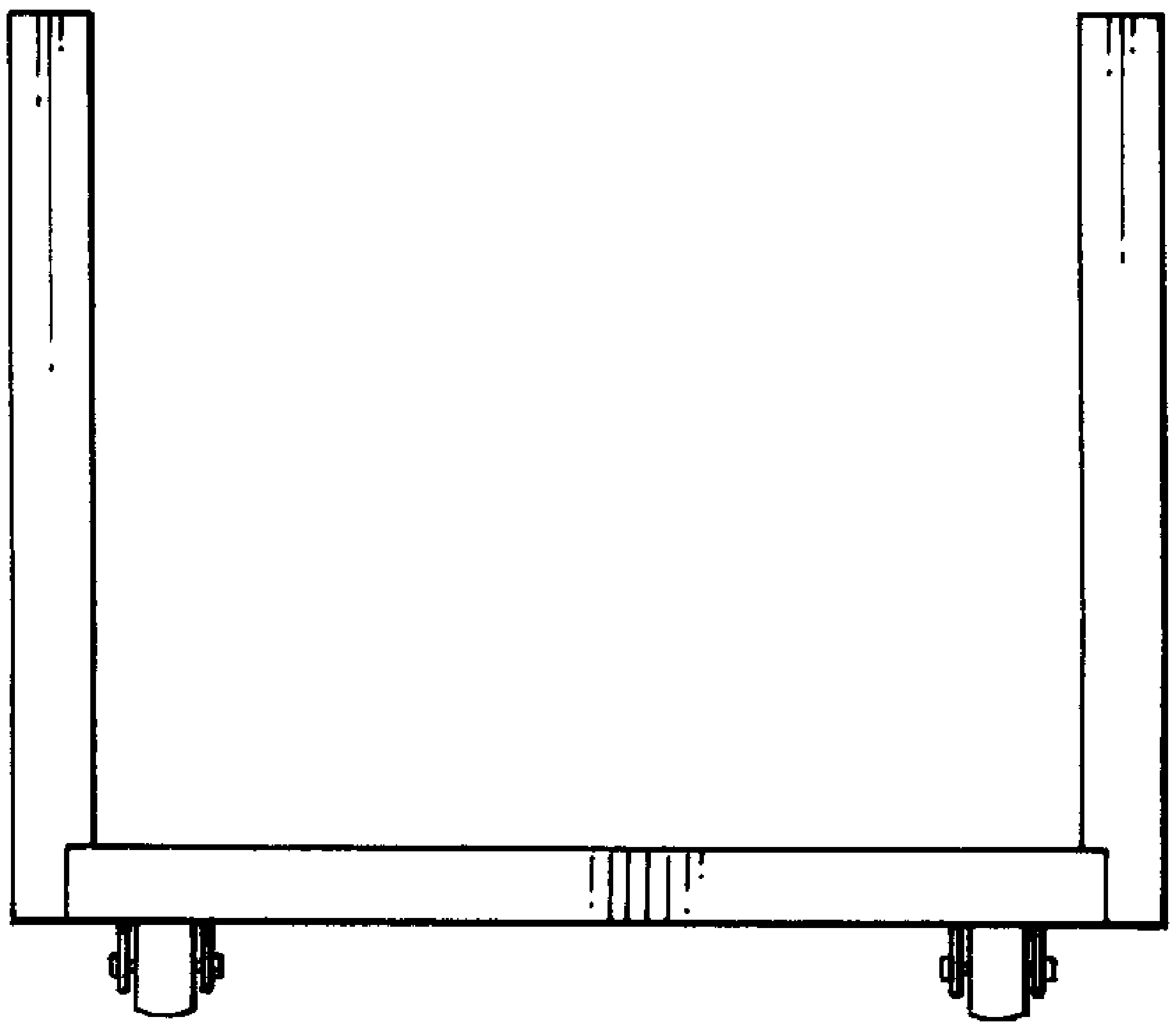


FIG. 17

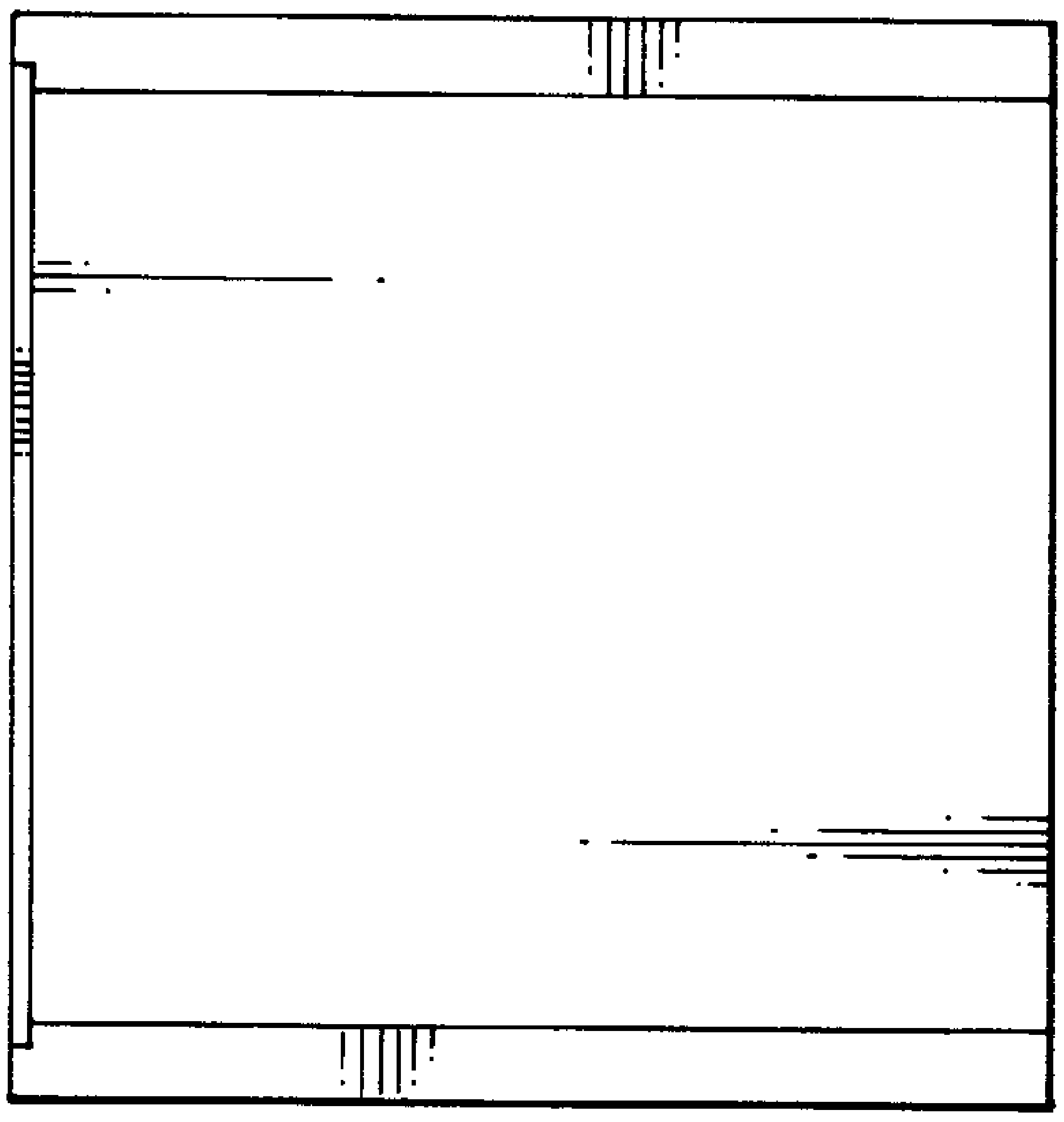


FIG. 18

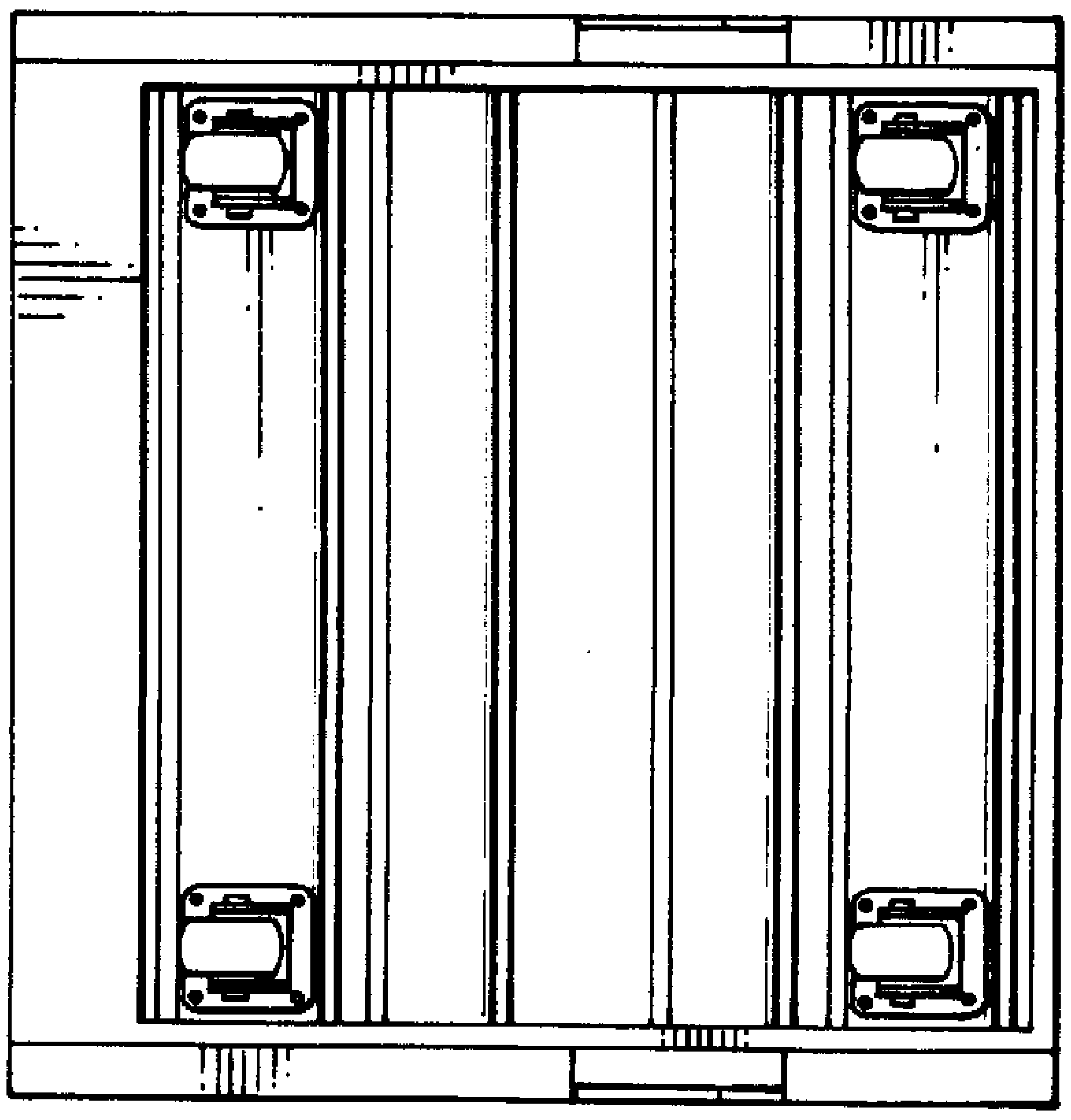
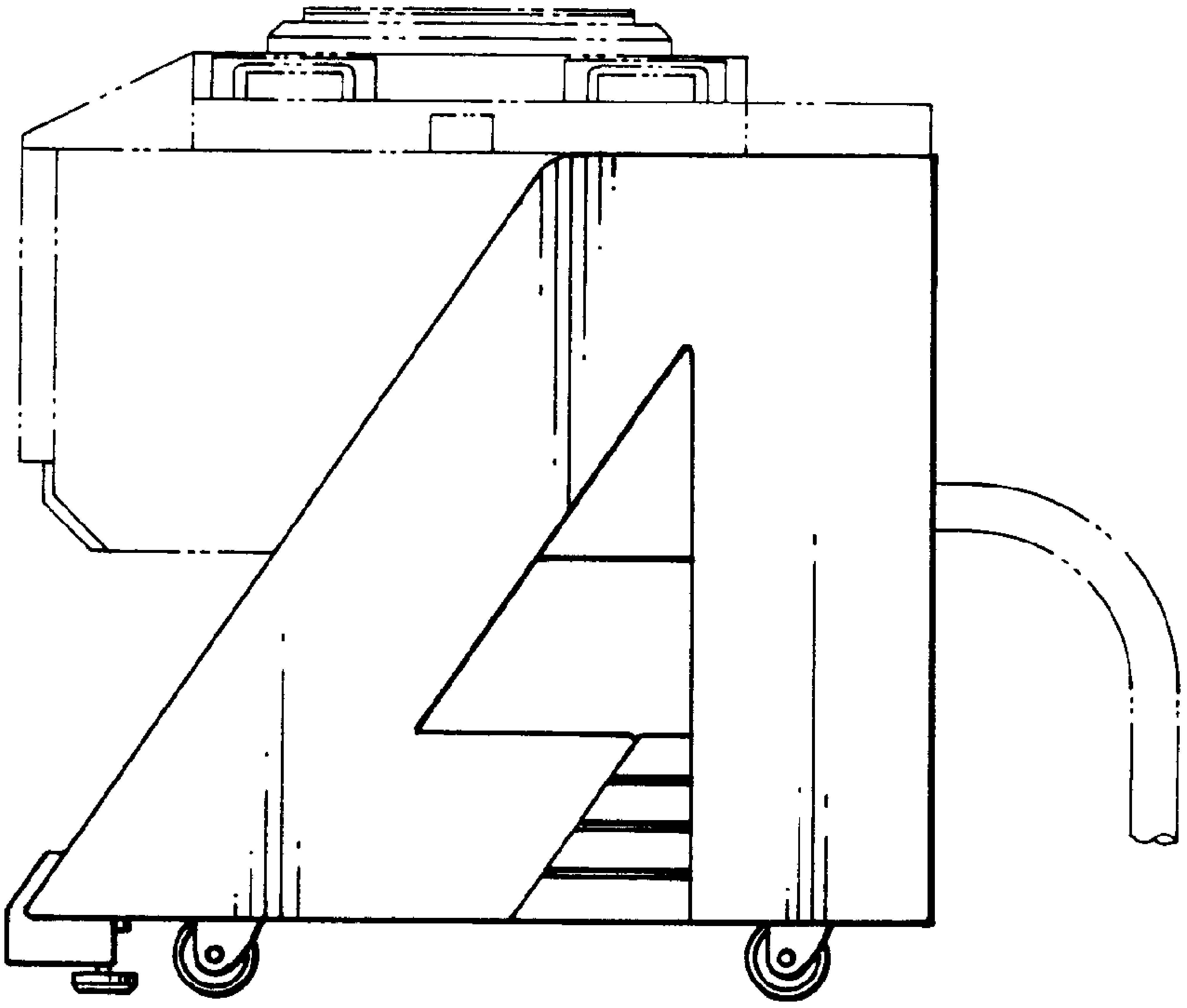


FIG. 19



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CERTIFICATE OF CORRECTION

Page 1 of 1

PATENT NO. :Des 420,927
DATED :February 22, 2000
INVENTOR(S) :Takayuki Yano

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Title Page:

Insert the following Priority Data :

"JAPAN 10-19566 July 7, 1998; JAPAN 10-19567 JULY 7, 1998, and JAPAN 10-19568 JULY 7, 1998".

Signed and Sealed this

Seventeenth Day of July, 2001

Attest:

Nicholas P. Godici

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Attesting Officer

Acting Director of the United States Patent and Trademark Office

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CERTIFICATE OF CORRECTION

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DATED : February 22, 2000
INVENTOR(S) : Takayuki Yano

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Title page,
Insert Item:

-- [30] **Foreign Application Priority Data**

JAPAN	10-19566	July 7, 1998;
JAPAN	10-19567	July 7, 1998; and
JAPAN	10-19568	July 7, 1998 --.

Signed and Sealed this

Seventh Day of December, 2004

Jon W. Dudas

JON W. DUDAS
Director of the United States Patent and Trademark Office